

Search Notes

Application/Control No.

10/821,909

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under
Reexamination

DOI, YOSHIKI

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	124R	1/23/2006	HN
330	295	1/23/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST UPDATE SEARCH	1/23/2006	HN